

**Search Notes**

Application No.

10/731,608

Examiner

Ernest F. Karlsen

Applicant(s)

KIM ET AL.

Art Unit

2829

**SEARCHED**

Class	Subclass	Date	Examiner
324	765 769 158.1 73.1	9/21/2004	E.F.K.
365	201	9/21/2004	E.F.K.
714	718	9/21/2004	E.F.K.
327	161 252 263	9/21/2004	E.F.K.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
324	765 158.1	9/21/2004	E.F.K.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
test adj mode same delay and semiconductor	9/21/2004	E.F.K.
memory with delay with test		